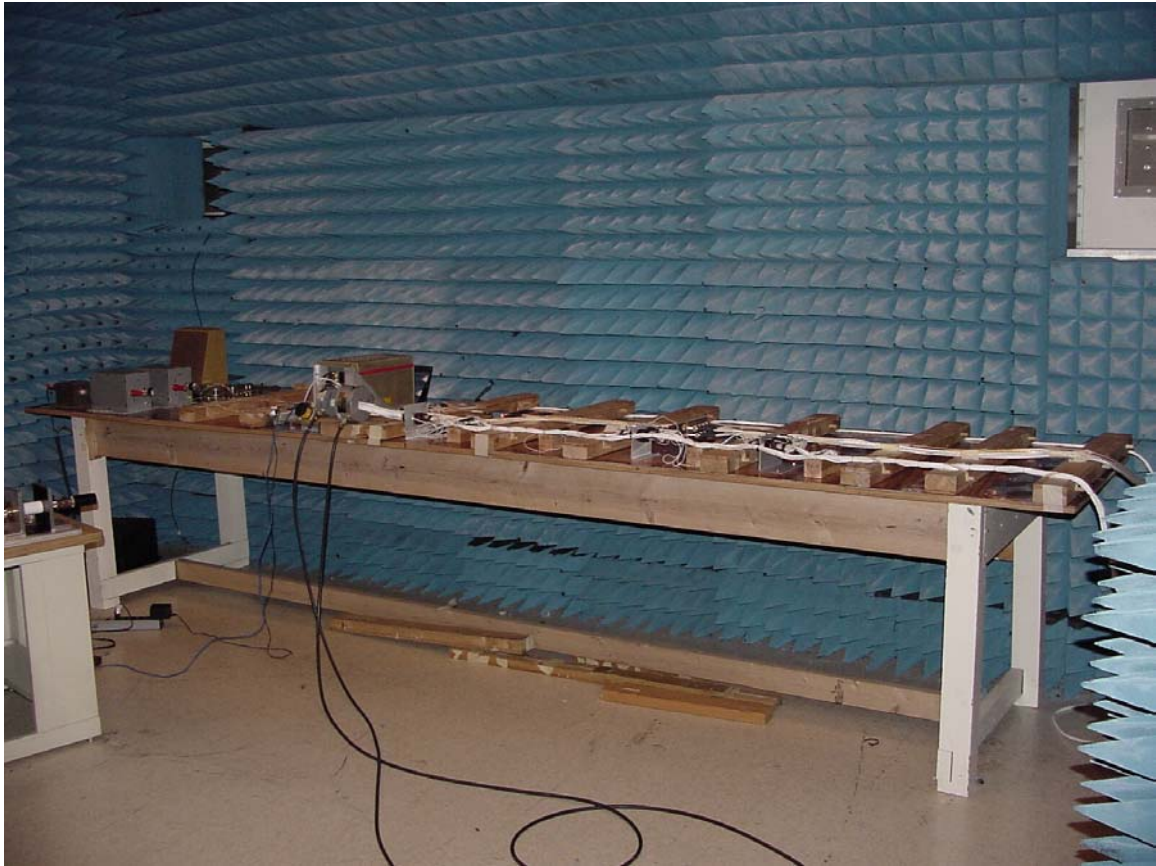




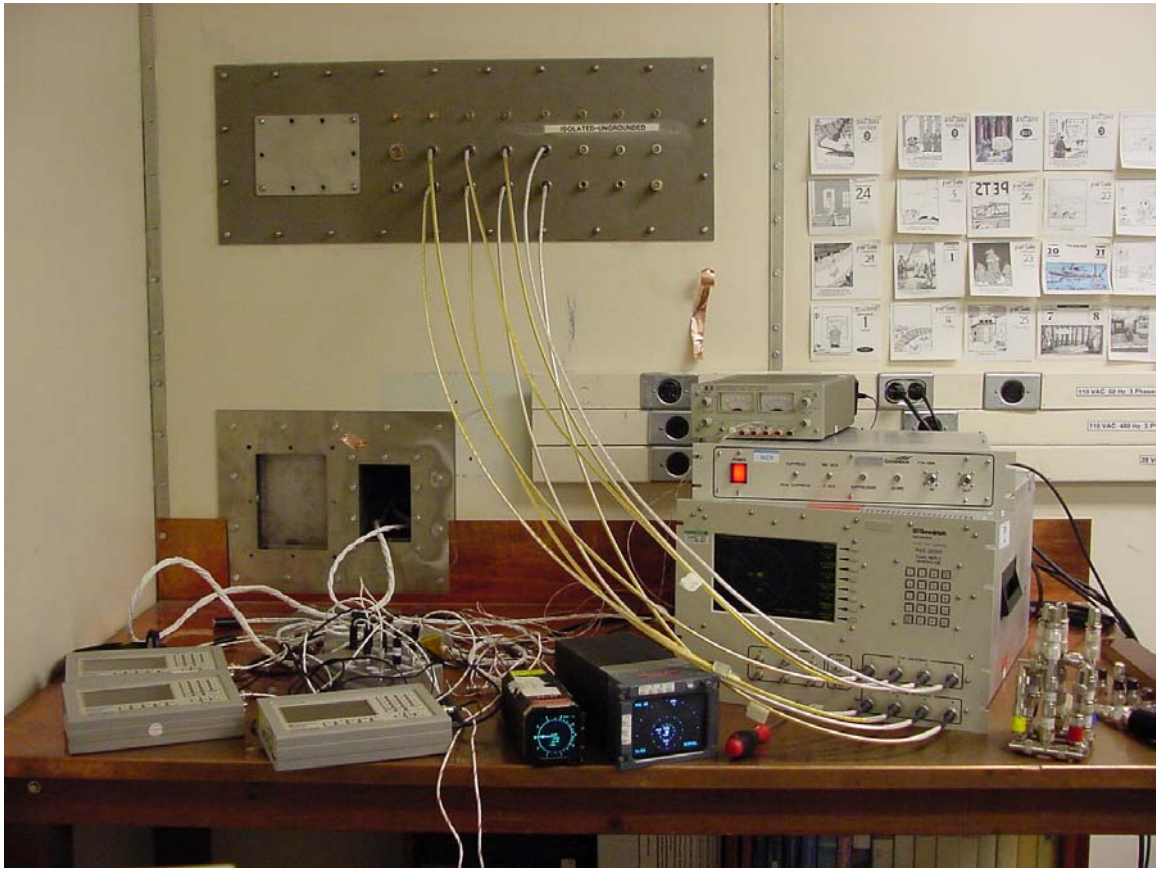
EMI Room test chamber



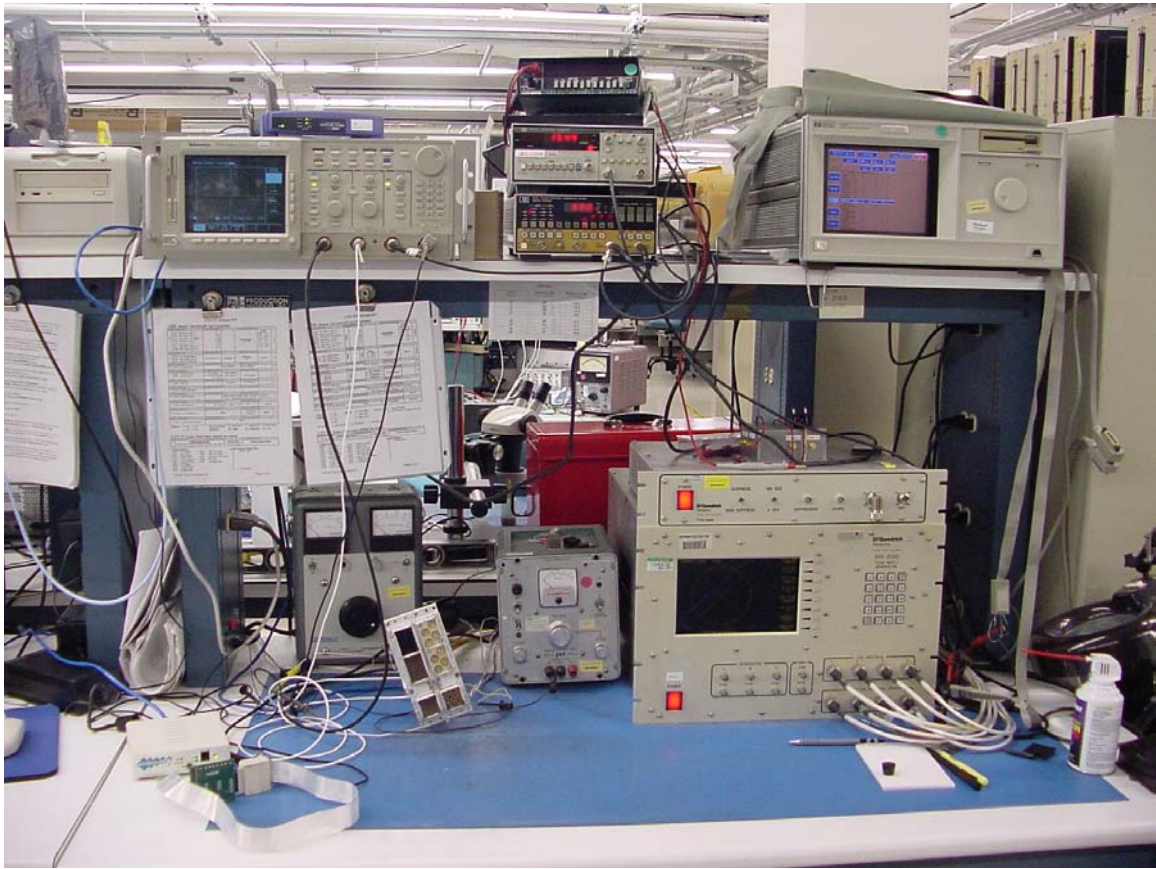
EMI Room test chamber showing TCAS harness.



EMI Room test chamber showing TCAS harness breakout into control room.



EMI Control room with TCAS test setup for control and monitoring processor during test.



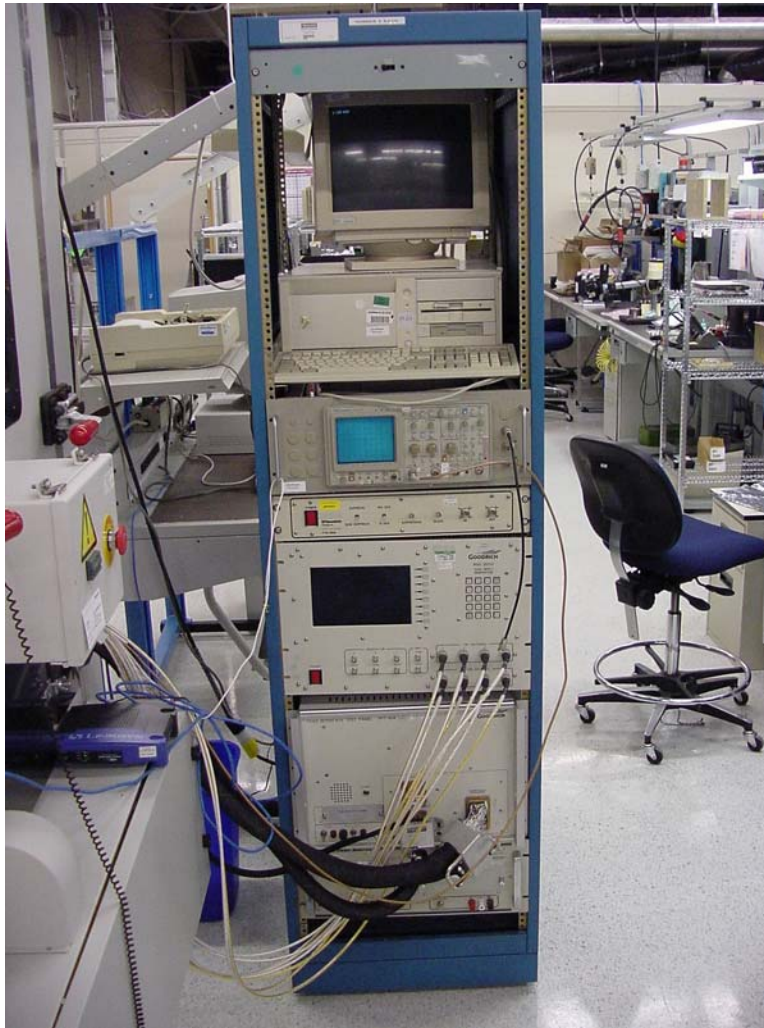
TPA-100A Signal Processor Test Station



Temperature and ATE test station



HALT Chamber (Highly Accelerated Life Test)



ATE test rack for monitoring TCAS operation during temperature tests.